Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/812,972	NIEN ET AL.
Examiner	Art Unit
Eric Chang	2116

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
EAST USPAT/PGPUB EPO/JPO	3/1/2007	EC
Consulted examiner James Trujillo	3/1/2007	EC